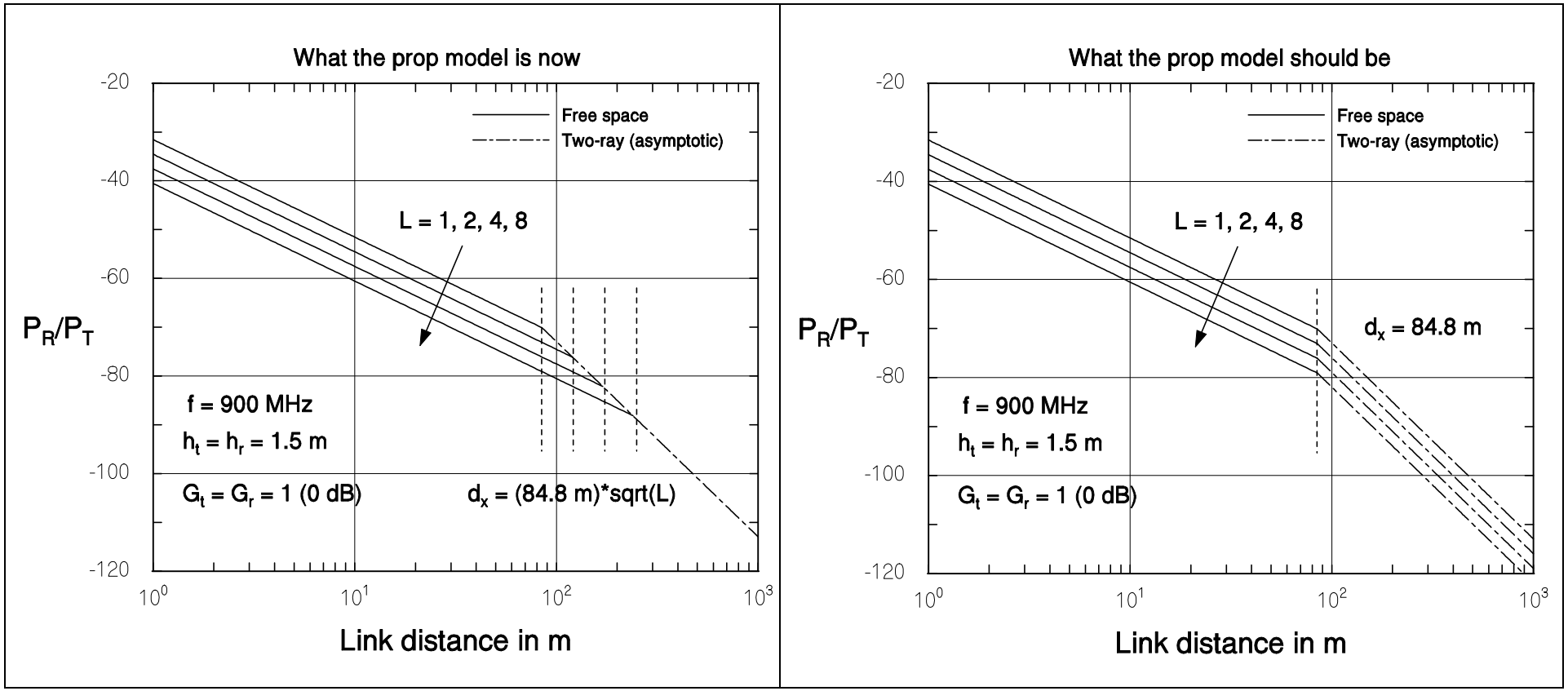

L. E. Miller, NIST
9/27/00